MTS 888

The difference between High Price and High Performance

The Evolution of Test

MTS 888

With the continuous and fast pace of development in electronic manufacturing the time from Design to Production has become crucial to the success or failure of a product. The time from Design to Test is a major part of this process and the MTS888 has been designed to speed up this process.

The direct translation of CAD data to test programs pioneered by Digitaltest in the early 80's reduced the time for fixture design from weeks to hours. But the fixture manufacturing process itself is still one of the most time consuming parts in the development of new test solutions.

The MTS888 has been developed so that fixture manufacturing can begin early in the product development cycle and it can be done in parallel with test program development. The solution is Non-Multiplexing. Existing test systems in the market call themselves non-multiplexed because they have a 1:1 pin architecture, but, in fact every 32 pins can only have the same logic family. Therefore before designing the fixture the user must know which nets are going to be involved in test and thus assign these pins according to their logic family either to the same driver sensor group or different ones. That approach leads back to test program first and then fixture design afterwards.

MTS888 redefines the term Non-Multiplexed by not just being a 1:1 pin architecture but furthermore allowing each tester pin to have its own logic family. This has become more and more important as the number of logic families on boards has increased in the last few years. But this is just one of the attractive features of the MTS888.

For years our precise programmable voltage levels provide excellent solutions for Low-Power Components such as 1,8V logic. Together with the intelligent Current-Control the MTS888 offers the most sophisticated pin architecture available.

Deep memory behind each pin, the intelligent data compression algorithm and the on the fly decompression of the data is another major advantage. Thus Boundary Scan, On board programming can be done through each tester pin.

The high fault coverage of the tester is guaranteed by the comprehensive component test library and the flexibility of the various test strategies such as In-Circuit, Functional, Boundary Scan, Flash Programming and Memory Test.

The main strength of the MTS tester family is the software platform that includes, among many unique features: CAD translators for over 60 different CAD formats, testability checks, fixture design, test program generation, extensive component test library, the Microsoft Visual Basic test language, Menu Aided Programming for functional test, graphical pattern editing and debugging, state of the art debugging tools using the board schematics and layout to debug the board, and a unique Test Coverage Report that provides analysis for test coverage of each single component and reflects the results in the board schematics.

digitaltest

Meeting Today's Dual demand of: High Performance and Economical Test

Specifications

In-Circuit Test

Analog ICT

	Digital ICT
3 Voltage/Current Sources with programmable current/ voltage limitation	One logic family per pin with programmable High and Low levels for drivers and sensors between +/-10V
0-10V DC-100kHz, 0-25V DC-100kHz and 0-100V DC	Every driver monitored through its own sensor
Measuring Voltage up to 25V DC-100kHz	Automatic Output Voltage Regulation
Measuring Current up to 100mA DC-100kHz	Backdriving Current +/-500mA
Measuring Voltage between ± 100V DC	Current permanently monitored by Pin Intelligence
Resistance 0.1 to 100MOhm	Pull-up/pull-down per Pin
Capacitance 1pF to 100mF	Up to 256K Memory behind each Pin
Inductance 10µH to 1000H	Intelligent Burst Data Compression and Decompression
Orientation of polarized Capacitors	All Bursts are loaded once in the Pin Memory
Connector Test	Up to 2M pattern per sec
Opens Detection of IC Pins	Prog. Inter Test Time and Inter Strobe Time
Test Speed up to 1000 Measurements per sec.	Loops, jumps, conditional jumps, subroutines
Comprehensive Component Test Library	Bus Commands, Count, CRC

Functional Test

Up to 6 prog. Power Supplies 9V/10A, 24V/5A,45/3.5A	Bus Communications (CAN,I2C,RS232,RS485, etc.)
DC Source DC measurement 0-±2V & 0-±25V	Open Collector Module
Frequency and Time Measurement Unit	User Test Module
Resistor Decade 1Ohm – 16MOhm	Memory Test Module
Function Generator up to 30MHz	Digital Multimeter

Software

Microsoft Windows NT&2000	Board Layout on Screen
Microsoft Visual Basic as a test language	Board Schematics on Screen
CITE Computer Integrated Test Environment	Measurement database and datalogging
C-LINK Link Design to Test	Test Coverage Report TCR
QMAN Quality Management System	Test stability Report QCAM

Innovation in Test

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Digitaltest GmbH
Lorenzstr. 3
D-76297 St.-Blankenloch
Germany
Tel. +49 (7244) 96 40 0
Fax +49 (7244) 96 40 90
E-mail: info@digitaltest.de

US Digitaltest Inc.
5046, Commercial Circle, Suite C
Concord, CA 94520
USA
Tel. +1 (925) 603 8650
Fax +1 (925) 603 8651
E-mail: sales@digitaltest.net

Digitaltest U.K. Ltd.
49 Cobham Road,
Ferndown Industrial Estate
Wimborne, Dorset BH21 7QZ
Tel. +44 1 (202) 89 27 55
Fax +44 1 (202) 89 55 64
E-mail:mbryant@digitaltest.co.uk

Digitaltest Asia Pte. Ltd.
Block 4009 Ang Mo Kio Ave. 10
01 - 34 TECHplace 1
Singapore 569738
Tel. +65 (645) 700 79
Fax +65 (645) 701 51
E-mail: singapore@digitaltest.net

Digitaltest SPB
Rigskij Prospect, 30/7 Liter A Flat 1-h
198023 St. Petersburg,
Russia
Tel.: +7 (812) 234 13 62
Fax: +7 (812) 234 13 62
E-mail: mail@digitaltest.ru

www.digitaltest.net